

**IN THE SPECIFICATION**

Please amend the portions of the Specification identified below to read as indicated herein.

**Paragraph beginning at page 5, line 19:**

Fourthly, the determination of the transfer function is strongly dependent on the quality of the reference-source ~~signal generator~~ 100 providing the reference signal 110. Any frequency limitation of the reference source 110 will automatically reduce the accuracy of the determined transfer function.

**Paragraph beginning at page 9, line 3:**

The upper part of Fig. 3 illustrates the calibration process preferably applied for determining the transfer function  $T(f)$  of the system 30. It is clear, however, that the transfer function  $T(f)$  can also be determined by other processes as known in the art, and that the invention is not limited to the specific embodiment as depicted in the upper part of Fig. 3. In accordance with the above said for Fig. 2, the first measuring device 130 measures and samples the signal response 120 of the system 30, while the second measuring device 140 measures and samples the reference signal 110 applied to the system 30. Also in accordance with the above said, a multiplication unit 200A provides an n-period signal from the sampled signal response 120, and a multiplication unit 200B provides an n-period signal from the sampled reference signal 110. The signal response 120 as well as the reference signal 110 are preferably sampled with highest accuracy achievable by the measuring-units ~~devices~~ 130 and 140. The n-periods signals from the multiplication units 200A and 200B are each modulated with a window function  $W$  and transformed into the frequency domain, as indicated by the respective blocks  $W$  and FFT, to a transformed signal response 210A and a transformed reference signal 210B.